



SPL-LABMAT s.r.o.

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CERTIFICATE OF CHEMICAL ANALYSIS No 05 – 23

DUCTILE CAST IRON for solid sample spectrometry, combustion and wet-way methods

SPL-L5 (PT 31/4A)

CERTIFIED VALUES – Mass content in %wt.

Element	Value [%wt.]	Uncertainty [%wt.]
C	3.833	0.020
Mn	0.407	0.003
Si	1.659	0.025
P	0.0461	0.0014
S	0.0123	0.0006
Cu	0.380	0.004
Cr	0.477	0.004
Ni	0.545	0.005
Al	0.036	0.002
Mo	0.208	0.002
W	0.0172	0.0013
V	0.183	0.002

Element	Value [%wt.]	Uncertainty [%wt.]
Ti	0.071	0.002
Co	0.0248	0.0008
As	0.0030	0.0006
Sn	0.0243	0.0011
B	0.0217	0.0005
Ca	<i>0.0003</i>	
Nb	0.0109	0.0009
Pb	0.0026	0.0004
Zn	0.0117	0.0008
Ce	0.0087	0.0016
Mg	0.0247	0.0016

PARTICIPATING LABORATORIES:

ACEMSA, Spain
AZTERLAN, Spain
CELSA HUTA OSTROWIEC, Poland
COGNOR S.A. - Ferrostal Łabędy, Poland
COMTES, Czech Republic
DUNAFERR Labor Nonprofit, Hungary
ENVIFORM, Czech Republic
ESAB CZ, Czech Republic
GONTERMANN-PEIPERS, Germany
LIBERTY Częstochowa, Poland

MS UTILITIES & SERVICES, Czech Republic
OBLF, Germany
SSAB, Sweden
ŠKODA AUTO, Czech Republic
TATA STEEL IJMUIDEN, Netherlands
TÜV NORD Czech, Czech Republic
ÚJV Řež, Czech Republic
VOESTALPINE STAHL, Austria
VÚHŽ-Foundry, Czech Republic
ZPS - SLÉVÁRNA, Czech Republic

SPL-L5 - ANALYTICAL DATA:

Method	C	Method	Mn	Method	Si	Method	P	Method	S	Method	Cu	Method	Cr	Method	Ni
AES	3,749							AES	0,0077						
AES	3,757							IR	0,0087						
AES	3,789							AES	0,0093						
AES	3,789							XRF	0,0103						
IR	3,795							AES	0,0104						
XRF	3,796							ICP	0,0110			AES	0,461	AES	0,520
IR	3,805	ICP	0,342*	ICP	1,451*	ICP	0,0374	ICP	0,0113	ICP	0,367	AES	0,461	AAS	0,521
IR	3,806	AES	0,396	XRF	1,573	AES	0,0394	IR	0,0113	IR	0,0113	AES	0,461	AAS	0,521
IR	3,808	ICP	0,400	Gravim.	1,578	AES	0,0412	XRF	0,0114	AES	0,370	AES	0,464	AES	0,524
ICP	3,814	AES	0,400	AES	1,587	ICP	0,0414	AES	0,0116	ICP	0,371	AES	0,465	AES	0,529
AES	3,820	AES	0,401	AES	1,587	XRF	0,0423	IR	0,0118	XRF	0,371	AES	0,467	XRF	0,529
IR	3,821	AES	0,402	AES	1,604	AES	0,0448	IR	0,0118	AES	0,373	AES	0,468	AES	0,534
AES	3,823	AES	0,403	XRF	1,616	ICP	0,0449	IR	0,0119	AES	0,374	ICP	0,468	AES	0,535
AES	3,825	AES	0,404	XRF	1,632	AES	0,0450	AES	0,0122	XRF	0,374	AAS	0,470	ICP	0,536
IR	3,826	AES	0,405	AES	1,641	ICP	0,0451	IR	0,0122	AAS	0,377	AES	0,473	XRF	0,542
AES	3,827	XRF	0,405	AES	1,643	XRF	0,0456	AES	0,0122	AES	0,377	AES	0,474	AES	0,543
AES	3,830	AES	0,405	ICP	1,643	XRF	0,0459	AES	0,0122	ICP	0,377	AES	0,475	XRF	0,544
IR	3,831	AES	0,405	AES	1,644	XRF	0,0460	XRF	0,0123	AES	0,378	AES	0,476	AES	0,545
IR	3,836	XRF	0,406	AES	1,647	AES	0,0460	AES	0,0124	AES	0,378	ICP	0,477	ICP	0,546
IR	3,839	ICP	0,407	Gravim.	1,668	AES	0,0462	IR	0,0125	XRF	0,380	AES	0,478	AES	0,547
IR	3,845	AES	0,407	AES	1,672	AES	0,0466	IR	0,0126	ICP	0,380	AES	0,478	AES	0,547
IR	3,846	AES	0,408	AES	1,672	AES	0,0478	IR	0,0126	AES	0,381	AES	0,479	ICP	0,549
AES	3,854	AES	0,408	AES	1,672	AES	0,0484	AES	0,0129	AES	0,382	AES	0,480	AES	0,550
IR	3,858	AES	0,408	AES	1,673	AES	0,0484	IR	0,0131	AES	0,382	AES	0,484	AES	0,551
IR	3,862	AES	0,409	AES	1,675	AES	0,0486	AES	0,0134	AES	0,382	AES	0,485	XRF	0,553
XRF	3,862	XRF	0,409	AES	1,679	AES	0,0487	XRF	0,0137	AES	0,383	AES	0,485	AES	0,553
AES	3,866	AES	0,410	AES	1,681	Photom.	0,0488	AES	0,0140	AES	0,384	AES	0,486	AES	0,554
AES	3,870	XRF	0,410	AES	1,687	AES	0,0488	IR	0,0142	AES	0,385	XRF	0,486	AES	0,555
IR	3,872	AES	0,411	AES	1,694	AES	0,0494	IR	0,0145	AES	0,386	AES	0,486	AES	0,557
IR	3,879	AAS	0,413	AES	1,695	AES	0,0500	AES	0,0146	AES	0,387	ICP	0,491	AES	0,562
AES	3,885	AES	0,413	AES	1,735	AES	0,0504	IR	0,0147	AES	0,389	XRF	0,496	ICP	0,563
AES	3,901	AES	0,414	AES	1,760	AES	0,0518	IR	0,0147	AES	0,395	XRF	0,521*	AES	0,564
IR	3,914	AES	0,415	XRF	1,780	AES	0,0671*	AES	0,0155	AES	0,397	ICP	0,526*	AES	0,568
	C		Mn		Si		P		S		Cu		Cr		Ni
Value	3,833		0,407		1,659		0,0461		0,0123		0,380		0,477		0,545
S_M	0,038		0,005		0,052		0,0035		0,0018		0,007		0,009		0,013
U	0,020		0,003		0,025		0,0014		0,0006		0,004		0,004		0,005

Method	Al	Method	Mo	Method	W	Method	V	Method	Ti	Method	Co	Method	As	Method	Sn
		ICP	0,185*			AES	0,176	AES	0,066						
		AES	0,197			AES	0,176	AES	0,068						
		AES	0,200			AES	0,177	ICP	0,068						
		AES	0,201			AES	0,177	AES	0,068						
AAS	0,030	AES	0,201			ICP	0,180	AES	0,069					AES	0,0198
AES	0,030	ICP	0,201			AES	0,180	AES	0,069					AES	0,0210
AES	0,033	AES	0,202			AES	0,180	AES	0,070					AES	0,0210
AES	0,033	AES	0,203			AES	0,180	XRF	0,070	ICP	0,0215			ICP	0,0221
AES	0,033	AES	0,203			AES	0,181	XRF	0,070	AES	0,0217			XRF	0,0228
AES	0,033	AES	0,203			AES	0,181	Photom.	0,070	ICP	0,0221			AES	0,0230
AES	0,034	AES	0,205			AES	0,182	AES	0,070	AES	0,0223			XRF	0,0231
AES	0,034	AES	0,205	AES	0,0132	AES	0,182	AES	0,070	AES	0,0238	AES	0,0010	AES	0,0231
AES	0,034	AES	0,206	AES	0,0135	AES	0,182	AES	0,071	AES	0,0240	AES	0,0013	AES	0,0232
AES	0,035	AES	0,206	AES	0,0141	XRF	0,183	AES	0,071	AES	0,0245	AES	0,0021	AES	0,0234
AES	0,035	XRF	0,207	AES	0,0155	AES	0,183	AES	0,071	AES	0,0247	ICP	0,0022	XRF	0,0238
AES	0,035	AES	0,208	AES	0,0159	ICP	0,183	AES	0,071	AES	0,0249	ICP	0,0023	AES	0,0239
AES	0,036	AES	0,209	XRF	0,0169	AES	0,183	XRF	0,072	ICP	0,0250	AES	0,0024	ICP	0,0240
AES	0,036	XRF	0,209	AES	0,0174	XRF	0,184	XRF	0,072	AES	0,0250	XRF	0,0028	AES	0,0244
AES	0,038	AES	0,210	AES	0,0174	AES	0,186	AES	0,073	AES	0,0252	AES	0,0028	ICP	0,0250
AES	0,038	AES	0,212	AES	0,0177	XRF	0,188	AES	0,073	AES	0,0254	AES	0,0028	AES	0,0250
AES	0,039	AES	0,213	AES	0,0179	XRF	0,188	AES	0,073	AES	0,0260	AES	0,0031	AES	0,0253
AES	0,039	AES	0,214	ICP	0,0179	ICP	0,188	ICP	0,073	AES	0,0260	XRF	0,0035	AES	0,0256
ICP	0,040	ICP	0,214	AES	0,0182	AES	0,189	ICP	0,074	AES	0,0260	AES	0,0036	AES	0,0256
AES	0,041	ICP	0,214	AES	0,0189	AES	0,189	AES	0,074	XRF	0,0264	AES	0,0036	AES	0,0257
AES	0,043	XRF	0,215	AES	0,0190	AES	0,190	AES	0,075	XRF	0,0267	ICP	0,0039	AES	0,0285
ICP	0,045	AES	0,218	XRF	0,0190	AAS	0,192	AES	0,076	AES	0,0272	AES	0,0047	AES	0,0296
ICP	0,046	AAS	0,220	AES	0,0226	AES	0,192	AES	0,082*	AES	0,0272	AES	0,0054	AES	0,0296
	Al		Mo		W		V		Ti		Co		As		Sn
Value	0,036		0,208		0,0172		0,183		0,071		0,0248		0,0030		0,0243
S_M	0,004		0,006		0,0024		0,005		0,002		0,0018		0,0011		0,0025
U	0,002		0,002		0,0013		0,002		0,002		0,0008		0,0006		0,0011

Method	B	Method	Ca	Method	Nb	Method	Pb	Method	Zn	Method	Ce	Method	Mg
				AES	0,0086								
				AES	0,0090	AES	0,0017	AES	0,0080				
				AES	0,0091	AES	0,0018	AES	0,0105				
AES	0,0200			AES	0,0092	ICP	0,0019	AES	0,0105		AES	0,0199	
AES	0,0208			AES	0,0096	XRF	0,0020	AES	0,0107		AES	0,0203	
AES	0,0210			XRF	0,0098	AES	0,0020	XRF	0,0107		AES	0,0206	
AES	0,0215			ICP	0,0099	ICP	0,0021	AES	0,0108	AES	0,0051	AES	0,0227
AES	0,0215			AES	0,0100	AES	0,0021	XRF	0,0108	AES	0,0058	AES	0,0244
AES	0,0217			AES	0,0105	ICP	0,0022	AES	0,0109	AES	0,0072	AES	0,0247
AES	0,0218			AES	0,0108	AES	0,0024	AES	0,0110	AES	0,0073	AES	0,0248
AES	0,0219	AES	0,0001	AES	0,0108	AES	0,0027	AES	0,0121	ICP	0,0081	AES	0,0250
AES	0,0221	AES	0,0002	AES	0,0110	AES	0,0027	AES	0,0123	AES	0,0081	AES	0,0253
ICP	0,0223	AES	0,0002	AES	0,0120	AES	0,0030	AES	0,0124	AES	0,0082	AES	0,0256
AES	0,0224	AES	0,0003	AES	0,0123	AES	0,0030	AES	0,0130	AES	0,0086	AES	0,0264
AES	0,0226	AES	0,0003	AES	0,0123	AES	0,0032	XRF	0,0131	ICP	0,0093	ICP	0,0265
AES	0,0226	AES	0,0004	AES	0,0124	AES	0,0032	AES	0,0134	AES	0,0106	AES	0,0270
AES	0,025*	XRF	0,0005	AES	0,0142	XRF	0,0036	AES	0,0135	AES	0,0126	AES	0,0270
AES	0,0253*	AES	0,0011	ICP	0,0154	ICP	0,0040	AES	0,0148	AES	0,0134	AES	0,0302
	B		Ca		Nb		Pb		Zn		Ce		Mg
Value	0,0217		0,0003		0,0109		0,0026		0,0117		0,0087		0,0247
S_M	0,0008				0,0019		0,0007		0,0016		0,0025		0,0028
U	0,0005				0,0009		0,0004		0,0008		0,0016		0,0016

COMMENTS:

Value – reference value, s_M – standard deviation of intralaboratory means (* - result excluded as outlier)

U – Uncertainty of the reference value $U \geq \pm \frac{t_{5;0,05}}{\sqrt{n}} \cdot s_M$ in the sense of the ISO Guide to the Expression of the Uncertainty of Measurement (1993), dependent on the standard deviation of the laboratory results.

Certified fully compliant with the ISO 17034 definition of Reference Material – with the characterization for determining the property values and their associated uncertainties.

Intended for calibration, matrix-match verification and statistical process control of cast iron spectrometric analysis from a plane of solid sample. They may not substitute CRM in a statement of metrological traceability, method validation. A single analysis area of at least 4 mm in diameter defines the minimum sample intake. They may be used for combustion and wet-way methods too.

Manufactured by casting to a special ingot with discarding of the parts, which have been suspected inhomogenous and the rest has been machined to the samples of the ultimate size.

Supplied as discs 37 mm in diameter and 25 mm of standard height.

Homogeneity (random and trend, within- and between- samples) was tested by various analytical techniques of adequate repeatability. Its uncertainty contribution, when statistically significant, was combined to the ultimate uncertainty statement. The RM are stable by a nature of material.

Characterised by results from SPL proficiency test **PT 31/4A** - laboratories by various spectrometric methods (AES spark, glow discharge, XRF) and alternative methods (combustion, thermoevolution, wet-way) standard methods, with measurements metrological traceable to adequate CRM (CZ 2001, 2003 - 2008, 2015-2024, BAS, Brammer Standard). Identity of PT participating laboratories is confidential.

Certified values in % m/m, tabulated below in bold, are robust means of a minimum five accepted laboratory means. They are rounded to the same digit as their uncertainty statement.

Uncertainty is expressed as a \pm half width interval combined from the standard uncertainty, expanded by the coverage factor $k = 2$ (corresponding to 95% level of confidence). It does not exceed 1,5 multiple of the typical uncertainty of the matching CRM.

Non-certified values in regular without the uncertainty statement do not meet the requirements for certification and are intended for the matrix information.

User instruction: the surface of the specimens and RM should be prepared in a similar manner in accordance with manufacturer's instructions of spectrometers. It is recommended to storage of RM in dry and non-corrosive conditions.

Produced by: SPL-LABMAT s.r.o.

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